


<b>Search Notes</b>  	<b>Application/Control No.</b>  10580352	<b>Applicant(s)/Patent Under Reexamination</b>  TAKASHI ET AL.
	<b>Examiner</b>  Stefan Kruer	<b>Art Unit</b>  3654

SEARCHED			
Class	Subclass	Date	Examiner
187	351,356,367,378,379, 371, 372, 374	03/30/2008	SHK
104	252, 257		
187	414	06/19/2008	SHK
B66B	5/00, 5/04, 7/00, 7/02		
104	127 - 128		

SEARCH NOTES			
Search Notes		Date	Examiner
PLUS		03/30/2008	SHK
248 + word			

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
US PGPUBS		06/19/2008	SHK